



CSTS225N04F N-Ch 40V Fast Switching MOSFETs

CSTS225N04F Features

- Split Gate Trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$

CSTS225N04F Product Summary



BVDSS	RDSON	ID
40V	1.1mΩ	225A

CSTS225N04F Applications

- DC-DC Converters
- Power management functions
- Synchronous-rectification applications

CSTS225N04F PDFN5060-8L Pin Configuration



CSTS225N04F Absolute Maximum Ratings ($T_A=25^{\circ}\text{C}$ unless otherwise noted)

Parameter		Symbol	Limit	Unit
Drain-source Voltage		V_{DS}	40	V
Gate-source Voltage		V_{GS}	± 20	V
Drain Current (Silicon limited)		I_D	225	A
Drain Current ^A	$T_C=25^{\circ}\text{C}$	I_D	130	A
	$T_C=100^{\circ}\text{C}$		82	
Pulsed Drain Current ^B		I_{DM}	390	A
Avalanche energy ^C		E_{AS}	450	mJ
Total Power Dissipation ^D		P_D	114	W
Thermal Resistance Junction-to-Case		$R_{\theta JC}$	1.1	$^{\circ}\text{C}/\text{W}$
Thermal Resistance Junction-to-Ambient ^E		$R_{\theta JA}$	20	
Junction and Storage Temperature Range		T_J, T_{STG}	$-55 \sim +150$	$^{\circ}\text{C}$



CSTS225N04F Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	40	48		V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=40V, V_{GS}=0V$			1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{GS}= \pm 20V, V_{DS}=0V$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.2	1.8	2.5	V
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=20A$		1.1	1.4	m Ω
		$V_{GS}=4.5V, I_D=20A$		1.7	2.3	
Gate Resistance	R_g	$V_{GS}=0V, V_{DS}\text{ Open}, f=1MHz$		2.7		Ω
Maximum Body-Diode Continuous Current	I_S				100	A
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{DS}=25V, V_{GS}=0V, f=300KHz$		8300		pF
Output Capacitance	C_{oss}			1510		
Reverse Transfer Capacitance	C_{rss}			130		
Switching Parameters						
Total Gate Charge	Q_g	$V_{GS}=10V, V_{DS}=32V, I_D=20A$		127		nC
Gate-Source Charge	Q_{gs}			35		
Gate-Drain Charge	Q_{gd}			26		
Reverse Recovery Chrage	Q_{rr}	$I_F=25A, di/dt=100A/us$		163		ns
Reverse Recovery Time	t_{rr}			100		
Turn-on Delay Time	$t_{d(on)}$	$V_{GS}=10V, V_{DD}=20V, I_D=25A$ $R_{GEN}=2\Omega$		22.5		
Turn-on Rise Time	t_r			6.7		
Turn-off Delay Time	$t_{d(off)}$			80.3		
Turn-off fall Time	t_f			26.9		

Note:

- The maximum current rating is package limited.
- Repetitive rating; pulse width limited by max. junction temperature.
- $V_{DD}=32V, R_G=25\Omega, L=0.5mH$, starting $T_J=25^{\circ}\text{C}$.
- P_D is based on max. junction temperature, using junction-case thermal resistance.
- The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25^{\circ}\text{C}$.



CSTS225N04F Typical Performance Characteristics

Figure.1 Typical Output Characteristics

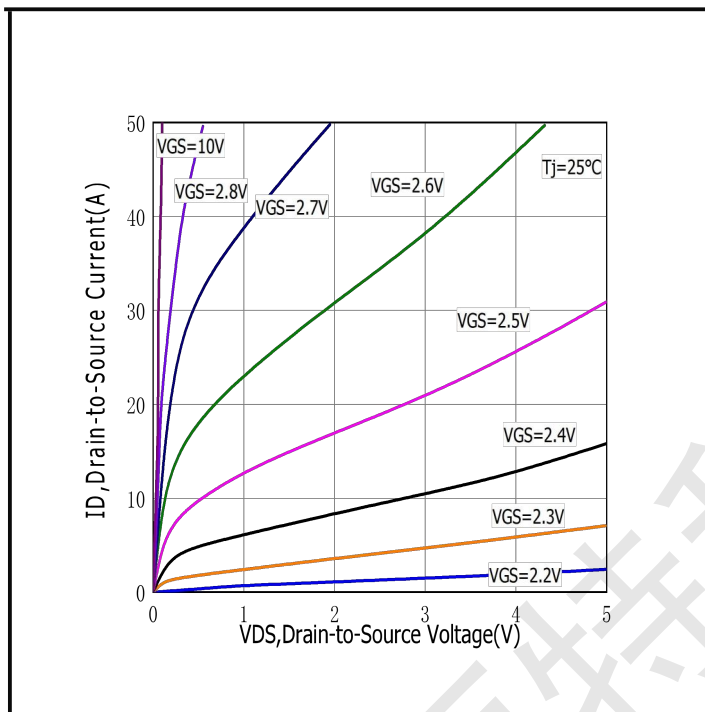


Figure.2 Typical Gate Charge vs Gate to Source Voltage

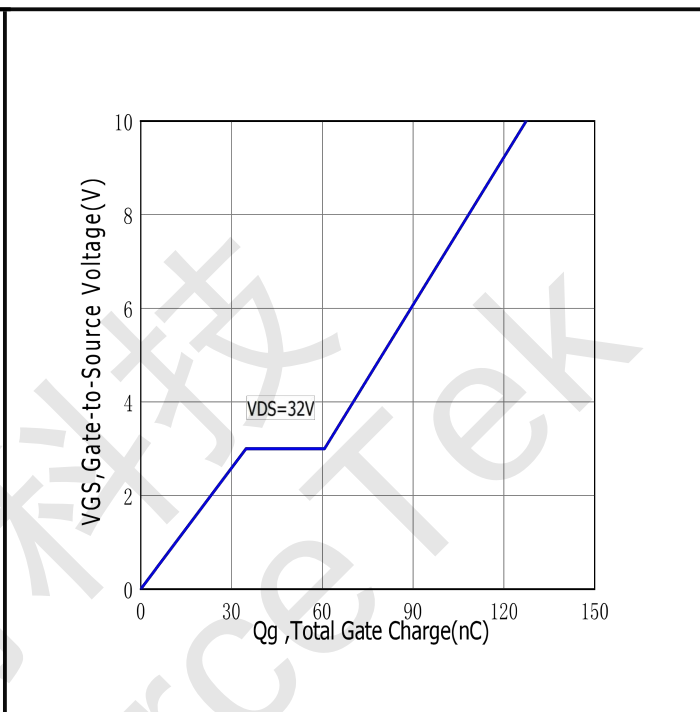


Figure.3 Typical Body Diode Transfer Characteristics

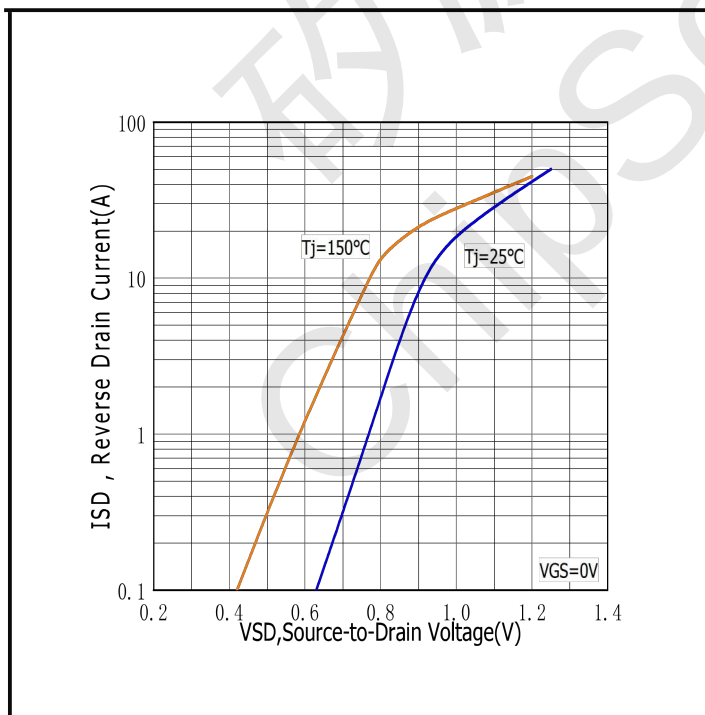


Figure.4 Typical Capacitance vs Drain to Source Voltage

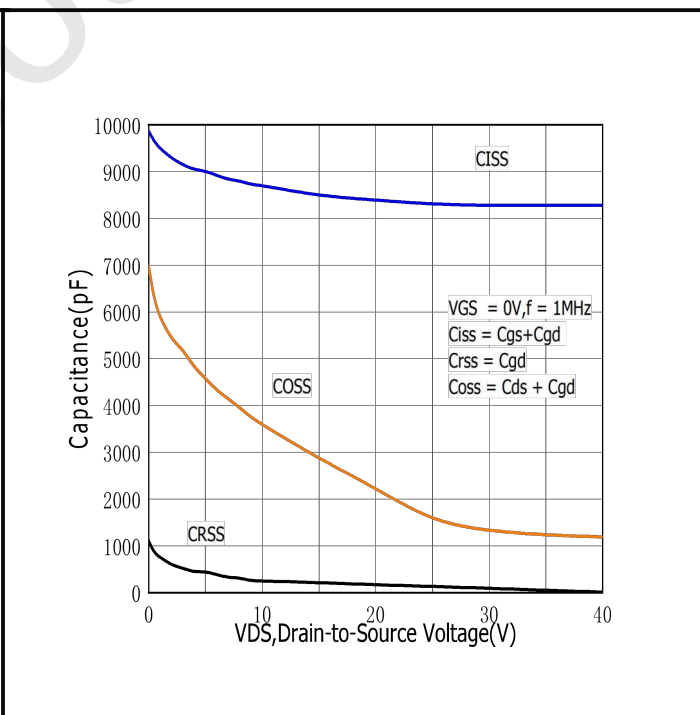




Figure.5 Typical Breakdown Voltage vs Junction Temperature

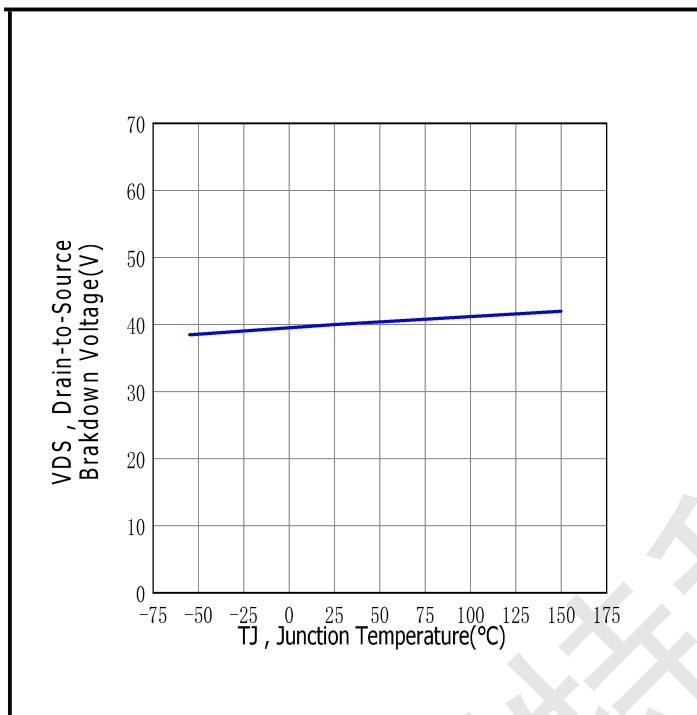


Figure.6 Typical Drain to Source on Resistance vs Junction Temperature

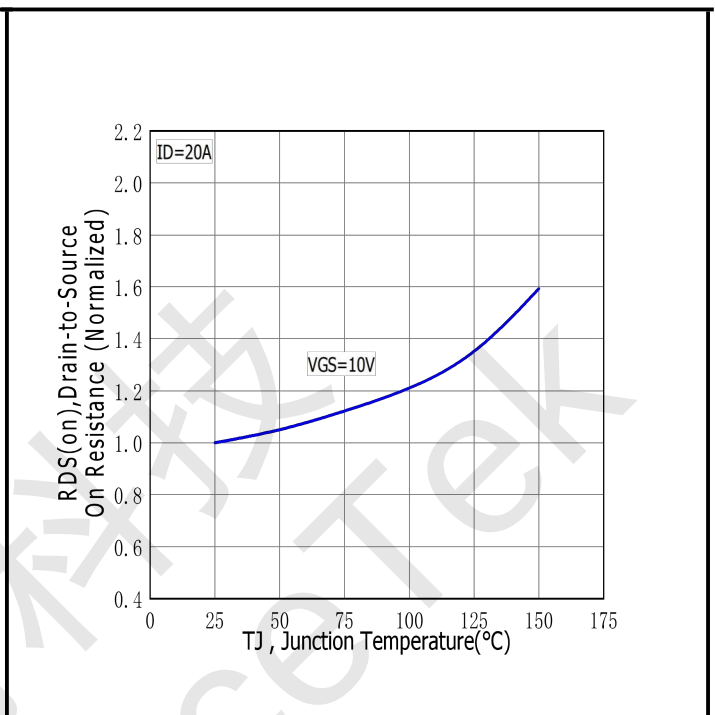


Figure.7 Maximum Forward Bias Safe Operating Area

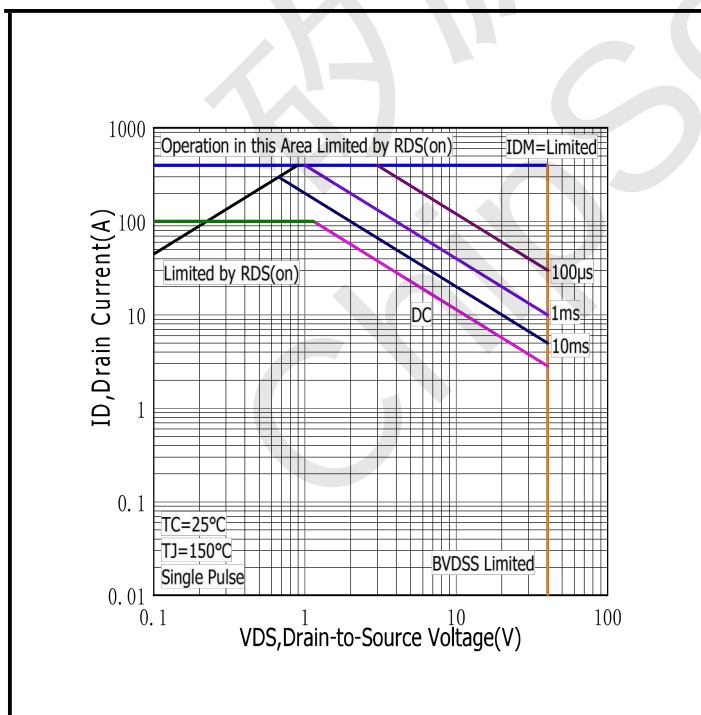
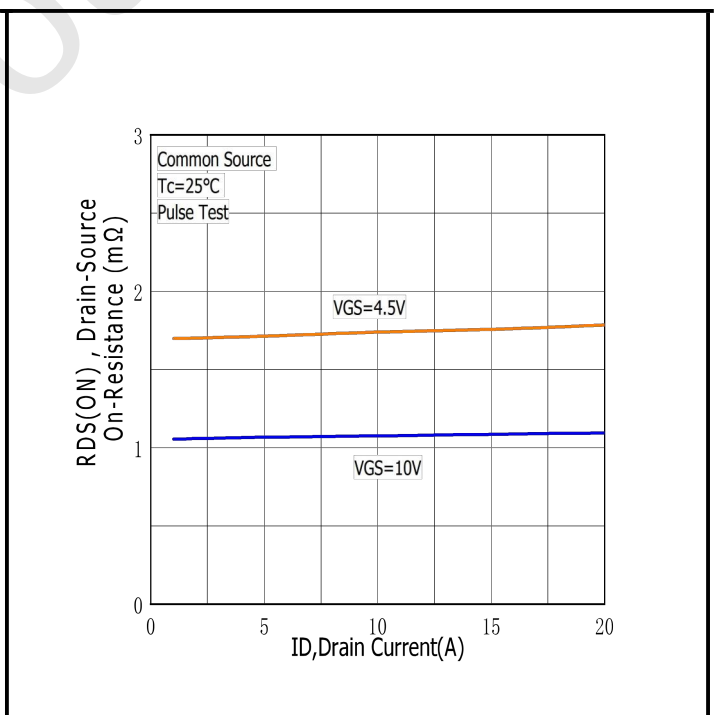


Figure.8 Typical Drain to Source ON Resistance vs Drain Current





CSTS225N04F Typical Performance Characteristics

Figure.9 Maximum EAS vs Channel Temperature

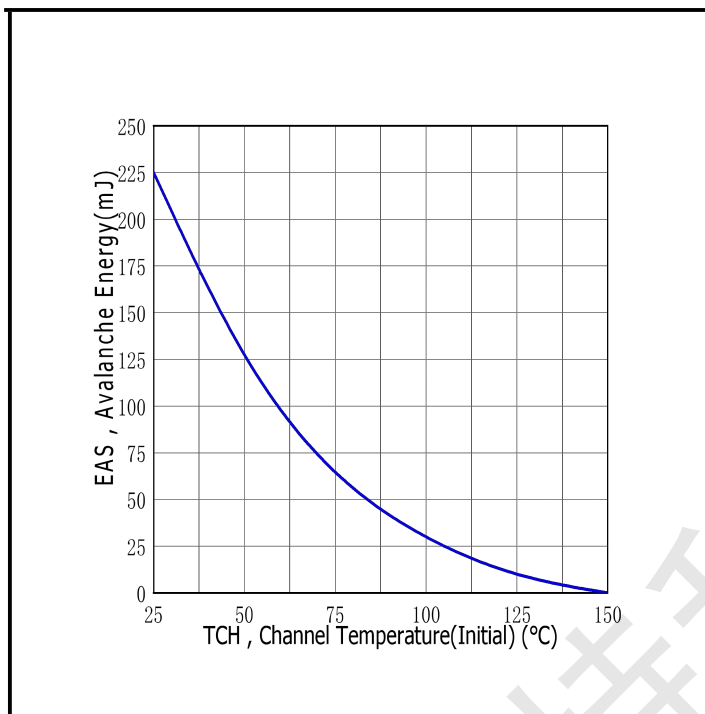


Figure.10 Typical Threshold Voltage vs Case Temperature

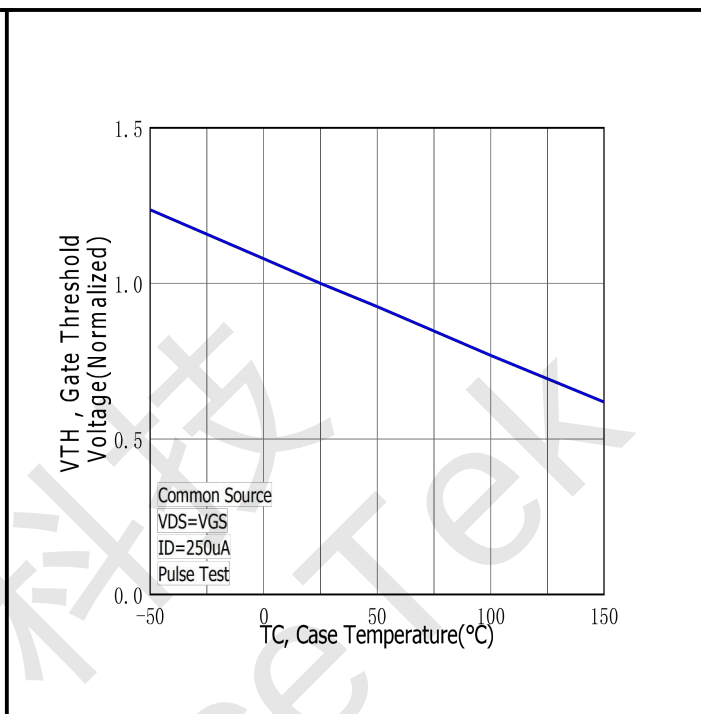


Figure.11 Typical Transfer Characteristics

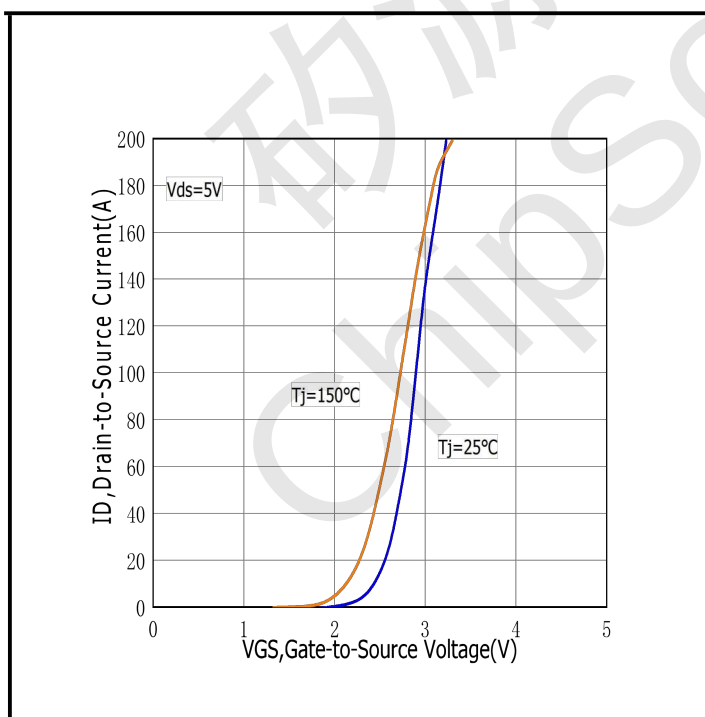


Figure.12 Maximum Power Dissipation vs Case Temperature

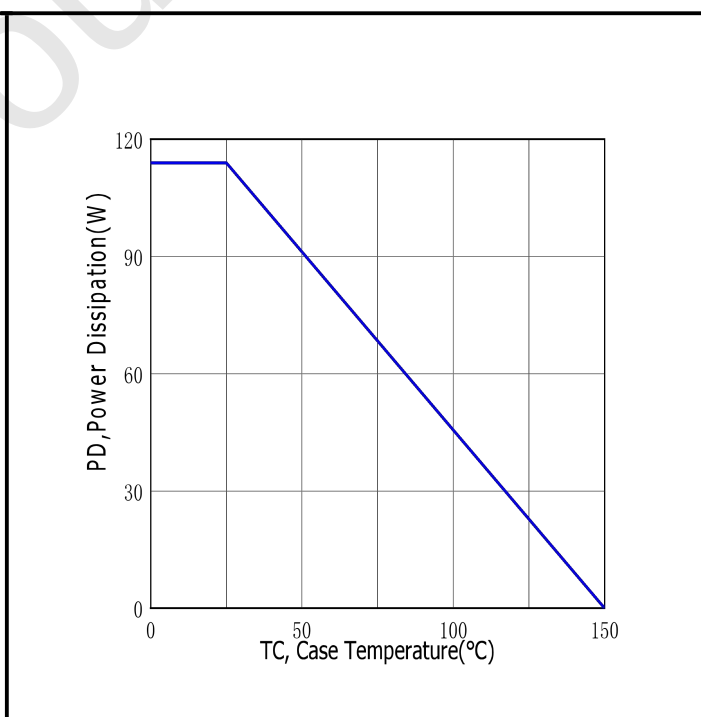
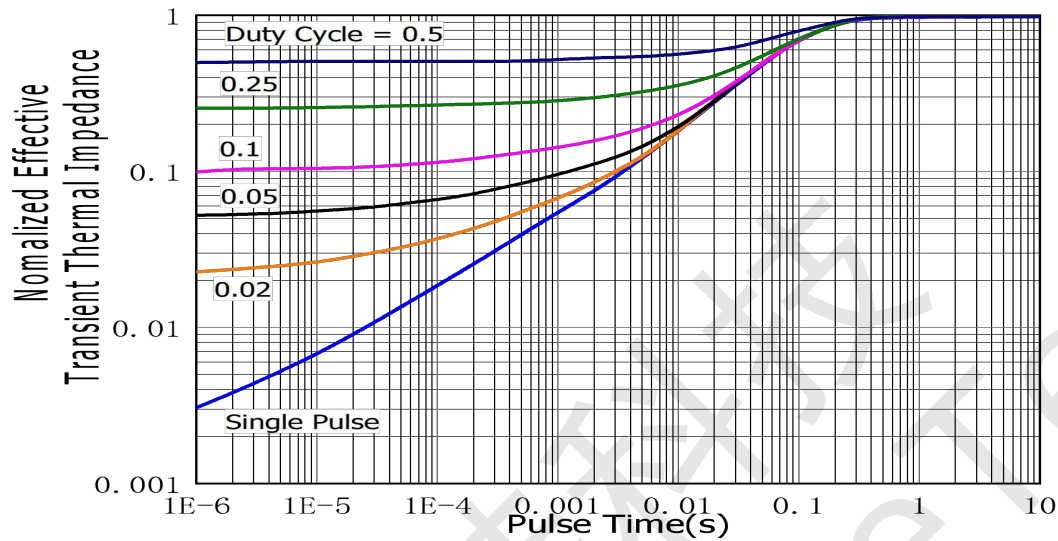




Figure.13 Maximum Effective Thermal Impedance , Junction to Case





CSTS225N04F Test circuits and waveforms

Figure A: Gate Charge Test Circuit & Waveforms

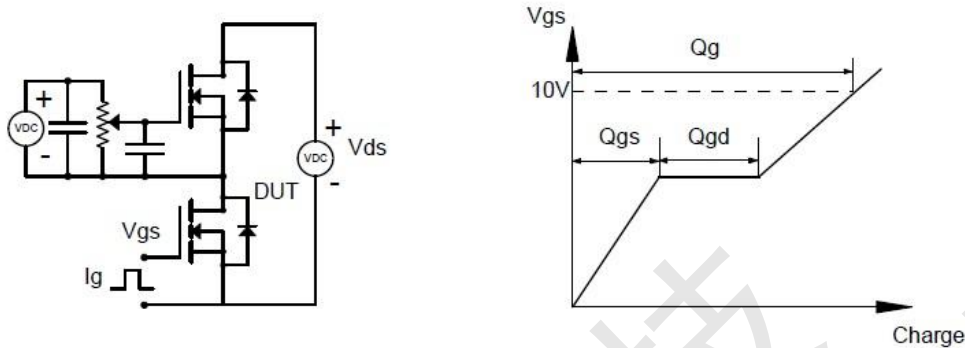


Figure B: Resistive Switching Test Circuit & Waveforms

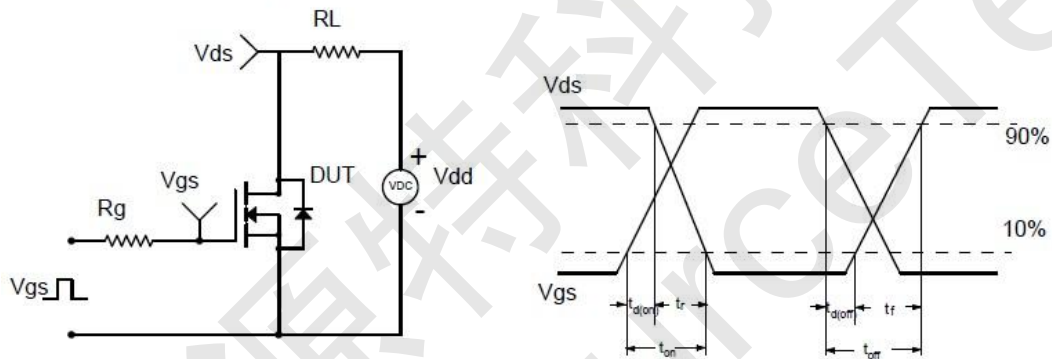


Figure C: Unclamped Inductive Switching (UIS) Test

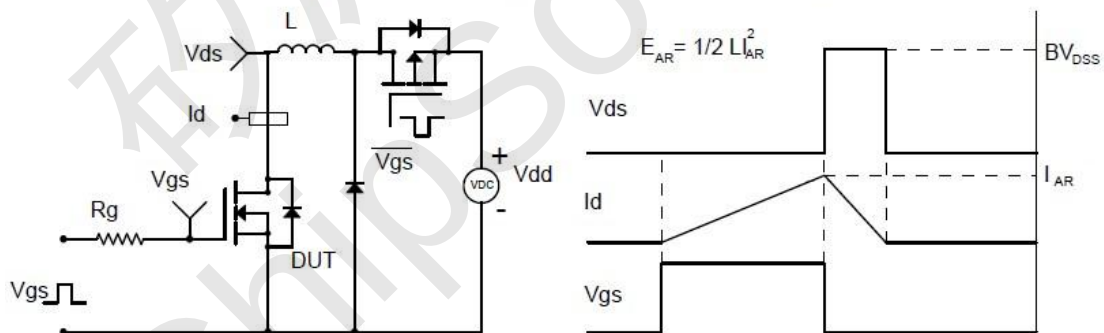
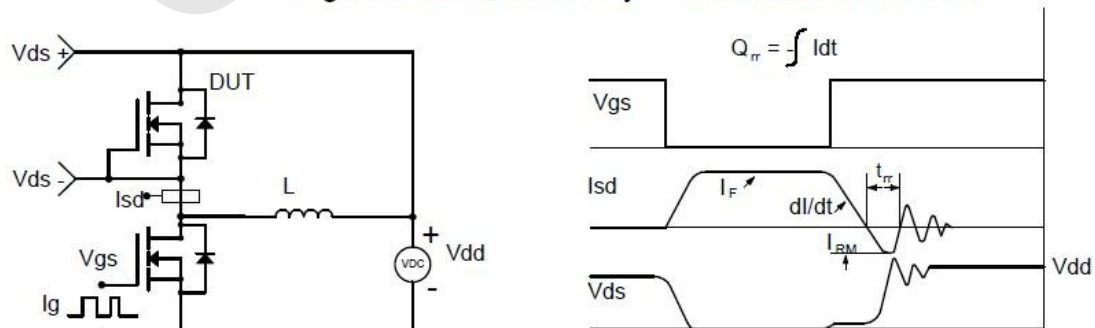
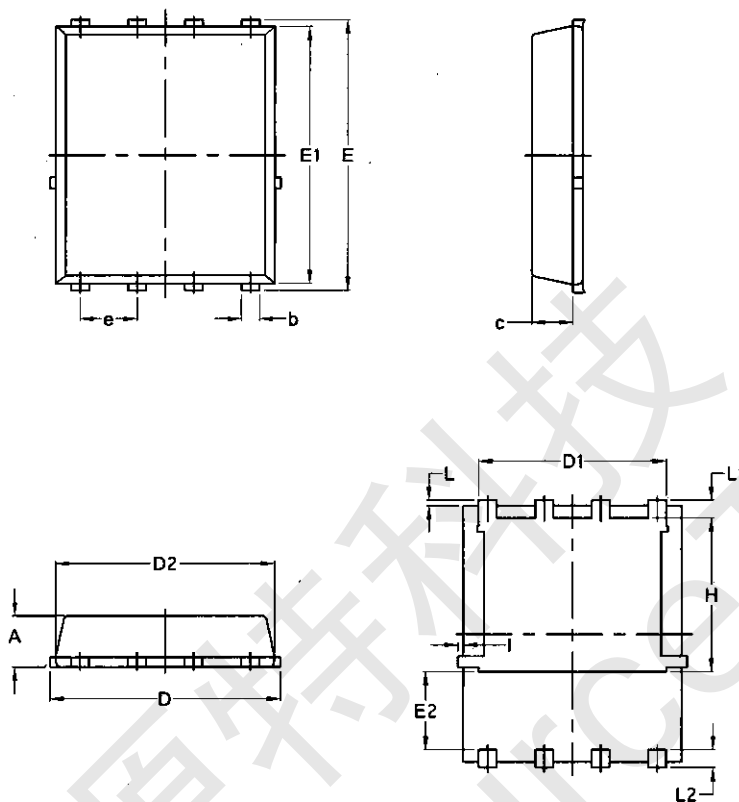


Figure D: Diode Recovery Test Circuit & Waveforms





CSTS225N04F Package Mechanical Data-PDFN5060-8L-JQ Single



Symbol	Common			
	mm		Inch	
	Mim	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070